PATENT ABSTRACTS OF JAPAN

(11)Publication number:

2003-264179

(43)Date of publication of application: 19.09.2003

(51)Int.Cl.

H01L 21/3065 H05H 1/00

(21)Application number: 2002-

(71)Applicant: TOKYO ELECTRON

066369

LTD

(22)Date of filing:

12.03.2002 (72)Inventor: TAKAYAMA NAOKI

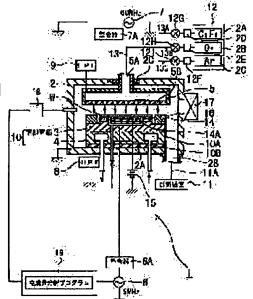
O TAKESHI

HARADA SATOSHI

(54) METHOD FOR DETECTING END OF SEASONING AND PLASMA TREATMENT METHOD

(57)Abstract:

PROBLEM TO BE SOLVED: To solve the problem of prior art analytic data that it is difficult to ascertain whether a variation becoming the decision criterion of the end of seasoning is a variation due to seasoning, i.e., a variation based on the state change in a treatment container, or a variation based on the temperature variation between dummy wafers and thereby it is difficult to make a decision whether seasoning has ended or not. SOLUTION: The method for detecting the end of seasoning when seasoning is performed by supplying dummy wafers W



into the treatment container 2 of a plasma treatment system 1 comprises a step for supplying the dummy wafers W into the treatment container 2, cooling the inside of the treatment container 2, and performing multivariate analysis using a plurality of data obtained when a plurality of dummy wafers W are supplied again into the treatment container 2 to formulate a formula for predicting the end of seasoning, and a step for detecting the end of seasoning when seasoning is